Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/037,755	CHO ET AL.	
Examiner	Art Unit	
Erin M. File	2611	

SEARCHED				
Class	Subclass	Date	Examiner	
375	261	5/4/2007	EMF	
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
EAST US PAT, USPGPUB, EPO, JPO DERWENT, IBM (text search only—see search history printout)	5/4/2007	EMF		
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